

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Joo-Ho KIM et al.

Application No.: Unassigned

Group Art Unit: Unassigned

Filed: March 24, 2005

Examiner: Unassigned

For: HIGH DENSITY RECORDING MEDIUM WITH SUPER-RESOLUTION NEAR-FIELD
STRUCTURE MANUFACTURED USING HIGH-MELTING POINT METAL OXIDE OR
SILICON OXIDE MASK LAYER

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

1. Enclosures accompanying this Information Disclosure Statement are:
 - 1a. ☒ Form PTO-1449.
 - 1b. ☒ Copy(ies) of IDS citation(s), except for U.S. Patents and U.S. Patent Application publications.
 - 1c. ☒ English language copy of a communication(s) from a foreign Patent Office or a PCT International Search Report.
 - 1d. ☒ English language translation (complete, Abstract or relevant portion(s)) attached to non-English language publications as indicated on the attached Form PTO-1449.
 - 1e. ☐ Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for providing a concise explanation of each non-English publication.
2. ☒ In accordance with 37 CFR § 1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is (Check appropriate Items 2a, 2b, 2c and/or 2d)
 - 2a. ☒ satisfied for the non-English language publication(s) cited on the enclosed "English language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP § 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, 8th Ed., Rev. 2)
 - 2b. ☐ set forth in the application.

10/529044
JC17 Rec'd PCT/PTO 24 MAR 2005

- 2c. ☒ an English language translation (Abstract only) attached to each non-English language publication as indicated on the attached Form PTO-1449.
- 2d. ☐ enclosed as Attachment 1(e), hereto.
3. No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 0001.1045	APPLICATION NO. 104529044
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		FIRST NAMED INVENTOR Joo-Ho KIM et al.	
		FILING DATE March 24, 2005	GROUP ART UNIT Unassigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
/KB/	AA	2002/0154596 A1	10/2002	HSU et al.			
	AB						
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO	ABSTRACT
/KB/	AF	KR 2000-14590	03/2000	Republic of Korea		X
/KB/	AG	JP 2000-285536	10/2000	Japan		X
/KB/	AH	WO 02/35540 A1	05/2002	WIPO		X
	AI					
	AJ					
	AK					

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

			TRANSLATION YES NO
/KB/	AL	YATSUI et al., "Increasing Throughput of a Near-Field Optical Fiber Probe Over 1000 Times by the Use of a Triple-Tapered Structure", Applied Physics Letters, Vol. 73, No. 15, Oct. 1998	
/KB/	AM	FUJII et al., "A Near-Field Recording and Readout Technology Using a Metallic Probe in an Optical Disk", Japanese Journal of Applied Physics, Vol. 39, Part I, No. 2B, February 2000, pp. 980-981	
EXAMINER /Kevin Bernatz/		DATE CONSIDERED 09/26/2008	
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			